

**Notice of References Cited**

Application/Control No.

09/577,551

Applicant(s)/Patent Under  
Reexamination  
DUNSHEE ET AL.

Examiner

Patrick D. Niland

Art Unit

1714

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**U.S. PATENT DOCUMENTS**

*		Document Number	Date	Name	Classification	
		Country Code-Number-Kind Code	MM-YYYY			
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	B	US-4334530	06-1982	Hassell	--	--
	C	US-				
	D	US-				
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	J	US-				
	K	US-				
	L	US-				
	M	US-				

**FOREIGN PATENT DOCUMENTS**

*		Document Number	Date	Country	Name	Classification	
		Country Code-Number-Kind Code	MM-YYYY				
	N	EP 596503	05-1994	EP	Miyamoto et al.	--	--
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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